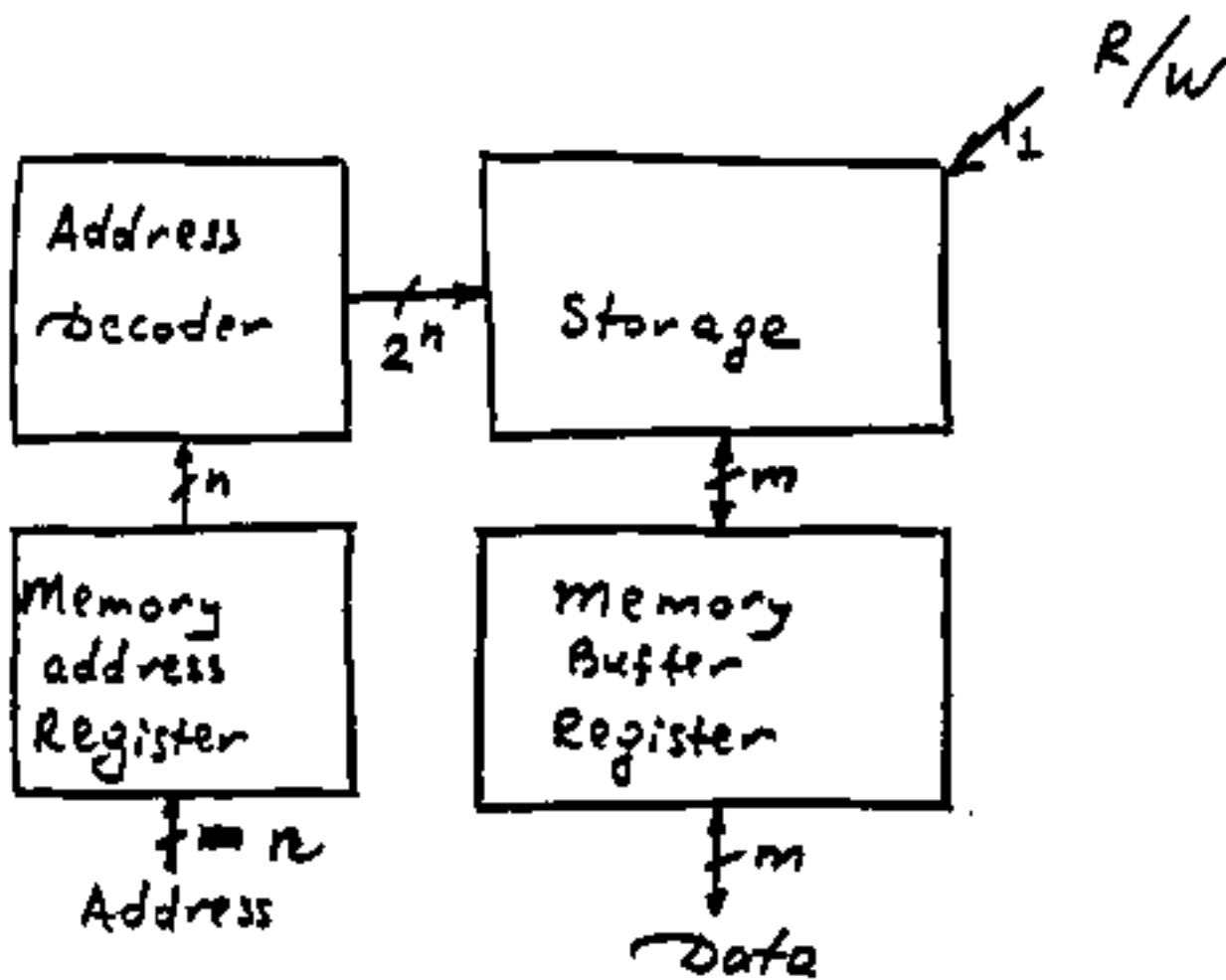


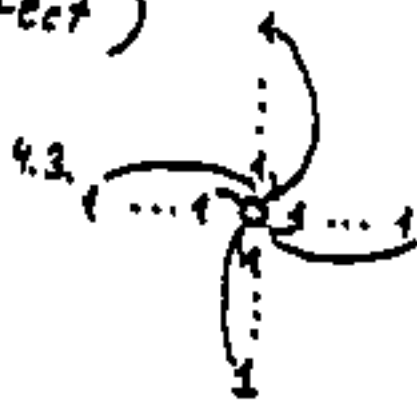
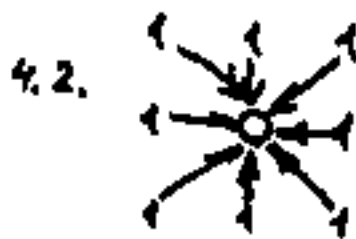
Memory Testing



Memory Organization

Faults in a Storage (Semiconductor memories)

1. Stuck-at faults in binary cells
2. Intermittent faults in cells
3. Row or column bridgings (AND or OR type)
4. Pattern sensitivity (crosstalks)
(most difficult to detect)



5. Hold-time errors \Rightarrow different cells have different hold-time \Rightarrow graceful degradation of performance

DATA RETENTION FAULTS

Decoding Errors

1. Wrong addressing.
2. No addressing
3. Multiple addressing

Test Complexity: $L(N)$ - number of
READ and WRITE operation
in a test

N - number of binary cells

For exhaustive test $L(N) \approx 2^N$ (unrealis)

For most testing procedures

$$C_1 N \leq L(N) \leq C_2 N^2$$

Goals of Memory Testing

1. Check the capability of each cell to store 0 and 1 (to avoid faulty cells) in computing mode). **LOCATE FAULTY CELLS.**
2. Check each cell for addressability & readability
3. Check for pattern sensitivity (crosstalks)
4. Check hold-times of each cell

DETERMINISTIC TESTS

Examples of Memory Testing Procedures 8.15

1. MSCAN

WRITE: $C_i \leftarrow 0$

READ: $C_i = 0$ (?) $i = 1, \dots, N$

WRITE: $C_i \leftarrow 1$

READ: $C_i = 1$ (?)

$$L(N) = 4N$$

detects stuck-at faults in cells

Van der Goor "Memory Testing"
Prentice Hall

2. Row/Column Bar

Column Bar:

WRITE 1010 ... 10
 1010 ... 10

 1010 ... 10

READ ↗

WRITE 0101 ... 01
 0101 ... 01

 0101 ... 01

(complimentary pattern)

READ ↗

$$L(N) = 4N$$

Detects stuck-at faults in cells, column/row bridgings, 50% of wrong addressings

3. Chessboard Test

WRITE

| | | | | | |
|---|---|---|---|---|---|
| 1 | 0 | 1 | 0 | 1 | 0 |
| 0 | 1 | 0 | 1 | 0 | 1 |
| 1 | 0 | 1 | 0 | 1 | 0 |
| 0 | 1 | 0 | 1 | 0 | 1 |
| 1 | 0 | 1 | 0 | 1 | 0 |
| 0 | 1 | 0 | 1 | 0 | 1 |

READ

WRITE

| | | | | | |
|---|---|---|---|---|---|
| 0 | 1 | 0 | 1 | 0 | 1 |
| 1 | 0 | 1 | 0 | 1 | 0 |
| 0 | 1 | 0 | 1 | 0 | 1 |
| 1 | 0 | 1 | 0 | 1 | 0 |
| 0 | 1 | 0 | 1 | 0 | 1 |
| 1 | 0 | 1 | 0 | 1 | 0 |

READ

$$L(N) = 4N$$

detects stuck-at faults in cells, row and column bridgings and some pattern sensitive errors (every 0 (1) surrounded by 1's (0's))

3) Marching 1's and 0's (GALPAT)

1) WRITE $C_i \leftarrow 0$ $i=0, 1, \dots, N-1$

2) For $i=0, 1, \dots, N-1$

READ $C_i = 0$?

WRITE $C_i \leftarrow 1$

READ $C_i = 1$?

3) For $i=N-1, N-2, \dots, 0$

WRITE $C_i \leftarrow 0$

READ $C_i = 0$?

4) Repeat 1)-3) ~~with~~ interchanging 0's and 1's

$$L(N) = 12N$$

Detects decoding errors, minimal check on cell interactions

4. Shifted Diagonal

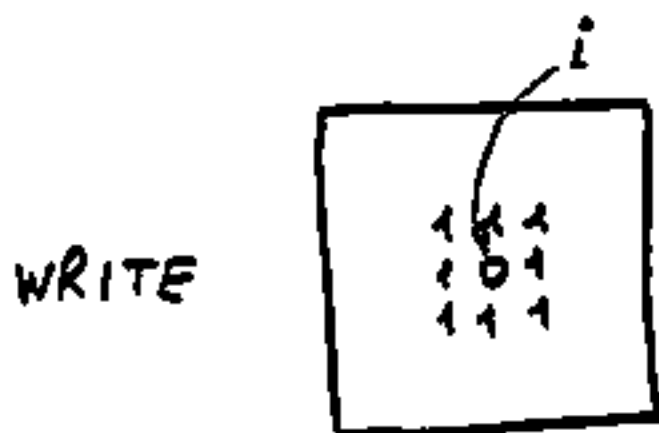
READ

WRITE complementary pattern.

READ complementary pattern

$$L(N) = 8 N^{3/2}$$

detects stuck-at faults, row and column bridgings, wrong addressing, pattern sensitive faults (every two cells in the same row or column are neighbours)

5. Ping-Pong Procedures5.1 Local Ping-Pong

$$i = 1, \dots, N$$

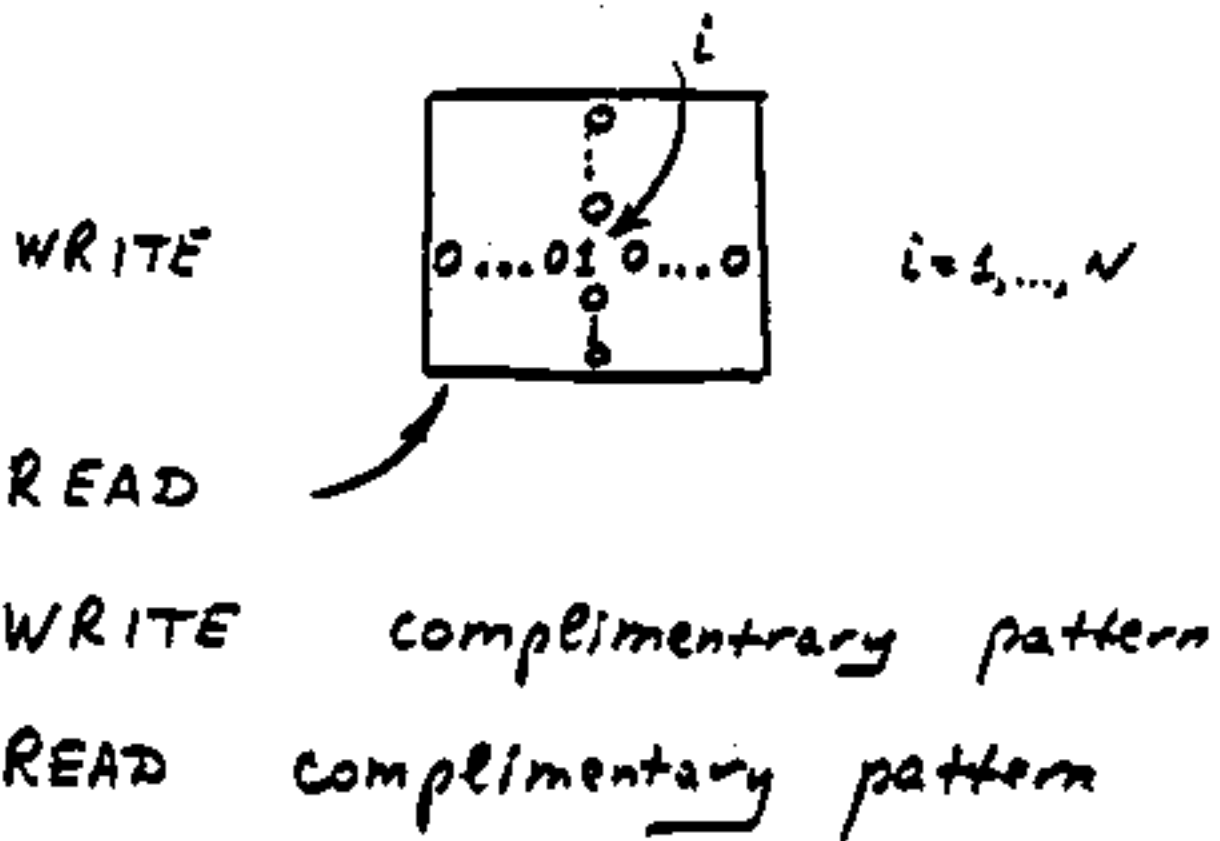
READ

WRITE complimentary pattern

READ complimentary pattern

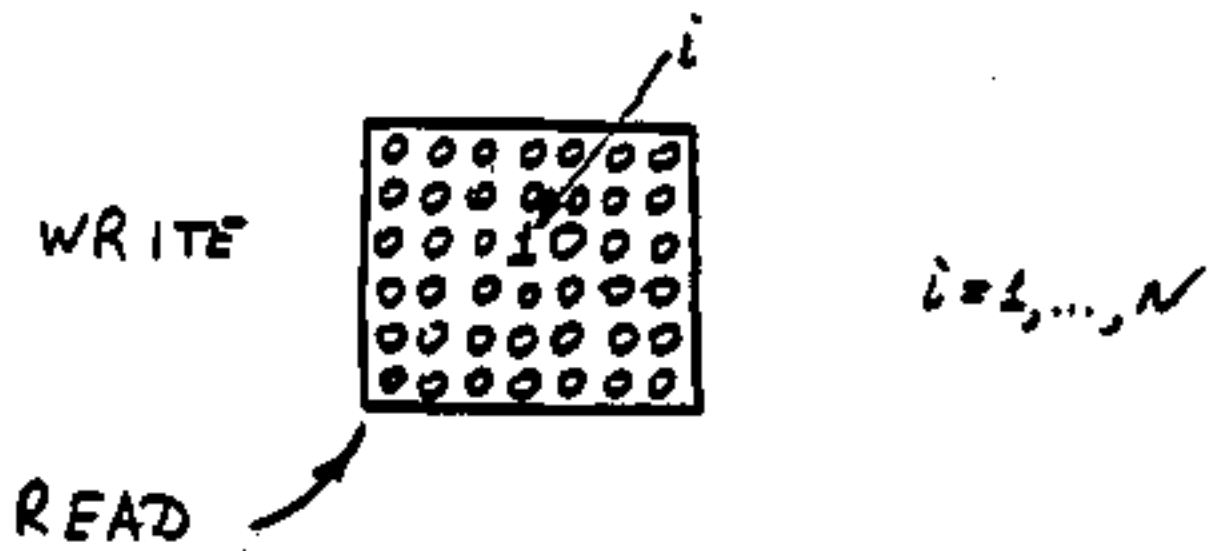
9 WRITES + 1 READ
for every i
FOR THE FIRST TWO
STEPS.

$$L(N) = 90N$$

5.2. Column / Row Ping-Pong

$$L(N) = 4N^{3/2} = 4N^{1.5}$$

5.3. Full Ping-Pong



WRITE complementary pattern.

READ complementary pattern

$$L(N) = 2N^2 + 2N$$

For ping-pong procedures

$$L(N) \approx 2Ns + 2N$$

s is the size of neighbourhoods

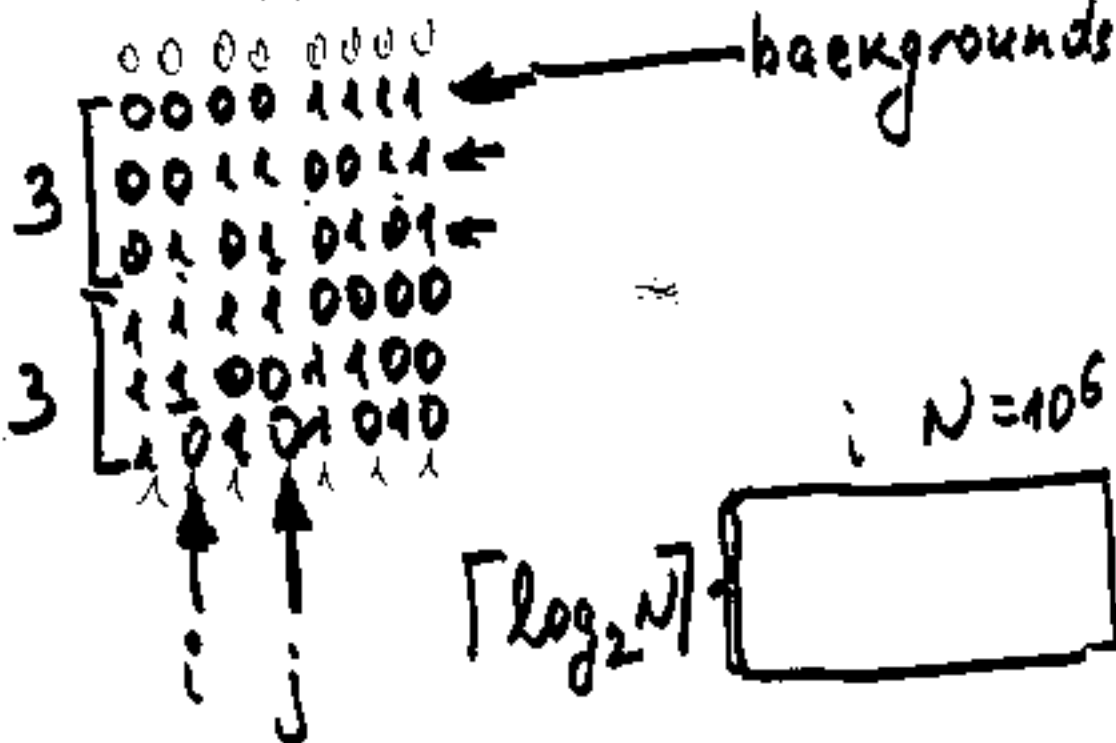
$k=2$ - couplings

STATIC PSFs
DYNAMIC

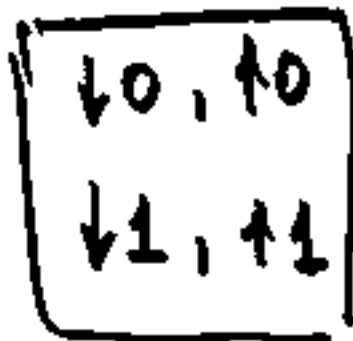
i, j

00
01
10
11

$N=8$



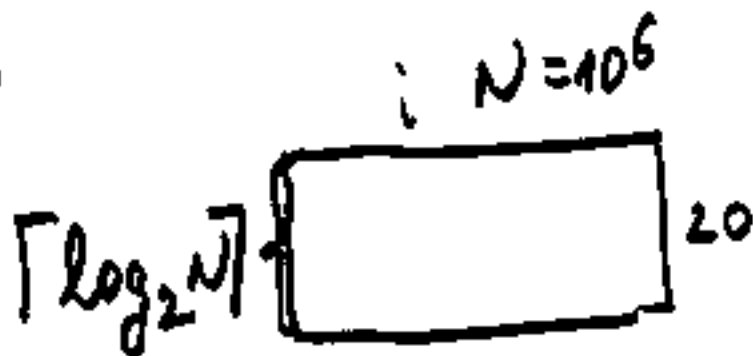
STATIC



DYNAMIC

$$L(N) = 2N \cdot 2 \lceil \log_2 N \rceil =$$

$$4N \log_2 N$$



$2 \lceil \log_2 N \rceil$ NUMBER OF BACKGROUNDS

k -couplings crosstalks between

any k cells in the memory

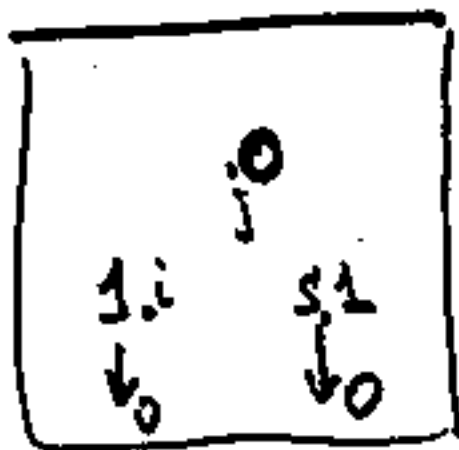
fix a pattern in $k \geq 2$ (KZ2)

change data in one cell \Rightarrow

data will be changed in another cell
of the k -tuple.

3-couplings

(i, j, s)



SCRAMBLING

TABLE ?

Summary on Test Complexities

1. Devices with constant complexity $T(m) = \text{const}$

M-input XOR gates, adders, subtractors

MAJORITY GATES, BIT-SLICE DEVICES

2. Devices with square root complexity

$$T(m) = c \sqrt{m}$$

Uniform NAND (NOR) trees

3. Devices with linear complexity $T(m) = cm$

M-input AND, OR, NAND, NOR gates

Reed-Muller networks, fanout-free networks

multiplexers, k out of m

4. Devices with exponential complexity

$$T(m) = c 2^m$$

2-level AND-OR (OR-AND) networks,

decoders

